Search Notes

Application/Control No.	Applicant(s)/Patent u	ınder
10/679,771	HAN ET AL.	
Examiner	Art Unit	
Richard H. Kim	2871	

Richard H. Kim

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
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SEARCH NOT (INCLUDING SEARCH)
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East Text Search (349/64,65)- jp,epo,uspat,pgpub-see search history printout	8/29/2007	RHK
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